

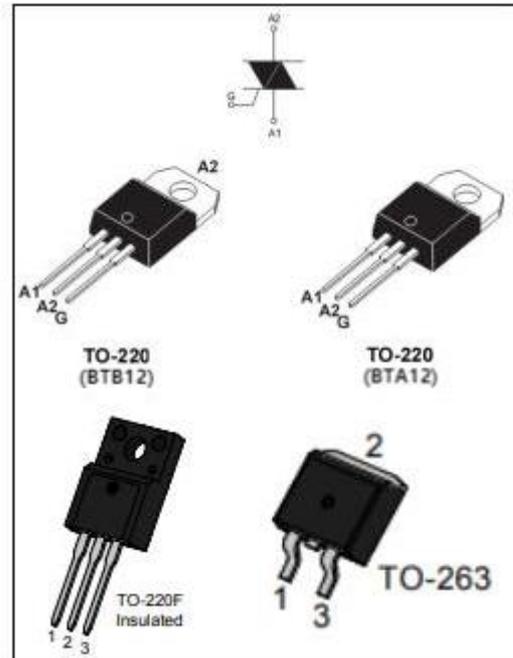


●Product features and main applications:

NPNPN five-layer structure of silicon bidirectional devices; with independent intellectual property rights of single-sided digging technology, table glass passivation process; multi-layer metallized electrodes on the back; with high blocking voltage and high temperature stability.

Mainly used in:

vacuum cleaners, power tools and other motor speed controllers; solid state relays; heating controllers (temperature regulation); other phase control circuits.



●Characteristics

Table 1. Absolute maximum ratings (Tj = 25 ° C unless otherwise stated)

Symbol	Parameter name		value	Unit
$I_{T(RMS)}$	RMS on-state current (full sine wave)	BTA BTB	Tc=80°C Tc=90°C	12 A
I_{TSM}	Non repetitive surge peak on-state current (full cycle, Tj initial = 25 ° C)	F=50HZ tp=20ms	120	A
I^2t	I2t value for fusing	tp=10ms	72	A ² S
di/dt	Critical rate of rise of on-state current IG = 2 x IGT, tr ≤ 100 ns	Tj=125°C	50	A/us



V_{DRM}/V_{RRM}	Off state repetitive peak voltage Reverse repetitive peak voltage	$T_j=25^{\circ}\text{C}$		600/800/1000	V
I_{GM}	Peak gate current	$t_p=20\mu\text{s}$	$T_j=150^{\circ}\text{C}$	4	A
$P_{G(AV)}$	Average gate power dissipation		$T_j=150^{\circ}\text{C}$	1	W
T_{stg} T_j	Storage junction temperature range Operating junction temperature range			-40to+150 -40to+125	$^{\circ}\text{C}$

● **Table 2. Electrical characteristics ($T_j = 25^{\circ}\text{C}$, unless otherwise specified) -- 3 quadrants**

Symbol	Name and test conditions	Quadrant	Range	value	Unit
I_{GT}	$V_D=12\text{V}$ $R_L=100\Omega$	I II III	MAX	≤ 50	mA
V_{GT}			MAX	1.5	V
V_{GD}	$V_D = V_{DRM}$, $R_L = 3.3\text{ k}\Omega$, $T_j = 125^{\circ}\text{C}$		MIN	0.2	V
I_H	$I_T = 100\text{ mA}$		MAX	60	mA
I_L	$I_G = 1.2 \times I_{GT}$		MAX	60	mA
				100	
dv/dt	$V_D = 67\% V_{DRM}$, gate open, $T_j = 125^{\circ}\text{C}$		MIN	500	V/us
(dv/dt) _c	Critical rise rate of commutation voltage $T_j = 150^{\circ}\text{C}$		MIN	8	V/us



●Table 3. Electrical characteristics ($T_j = 25\text{ }^\circ\text{C}$, unless otherwise specified) - Standard Triac (4 quadrants)

Symbol	Name and test conditions	Quadrant	Range	value	Unit	
I_{GT}	$V_D=12V$ $R_L=100\Omega$	I II III IV	MAX	I II III	IV	mA
				$\cong 50$	$\cong 120$	
V_{GT}	MAX		1.5		V	
V_{GD}	MIN		0.2		V	
I_H	$I_T=500mA$		MAX	60	mA	
I_L	$I_G = 1.2 \times I_{GT}$		MAX	60	mA	
			MAX	100		
dv/dt	$V_D = 67\% V_{DRM}$, gate open, $T_j = 125\text{ }^\circ\text{C}$		MIN	500	V/us	
(dv/dt) _c	Critical rise rate of commutation voltage $T_J = 150\text{ }^\circ\text{C}$		MIN	10	V/us	



● Static parameters

Symbol	Parameter name			value	Unit
V_{TM}	$I_{TM} = 24A$	$T_j = 25^\circ C$	MAX	1.50	V
V_{T0}	threshold on-state voltage	$T_j = 150^\circ C$	MAX	0.86	V
R_d	Dynamic resistance	$T_j = 150^\circ C$	MAX	36.6	$m\Omega$
I_{DRM} I_{RRM}	VDRM = VRRM	$T_j = 25^\circ C$	MAX	5	μA
		$T_j = 150^\circ C$		1	mA
$R_{th(j-c)}$	Junction to ambient	BTA		2.05	$^\circ C/W$
		BTB		1.25	



● BT138-800 characteristic curve

FIG.1 Maximum power dissipation versus RMS on-state current

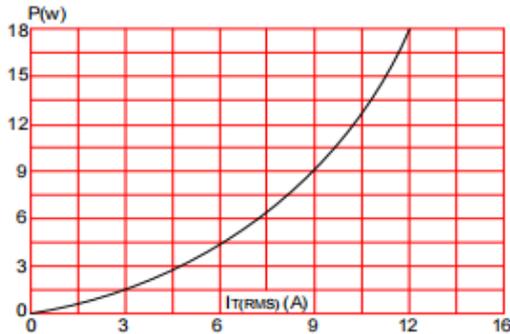


FIG.2 RMS on-state current versus case temperature

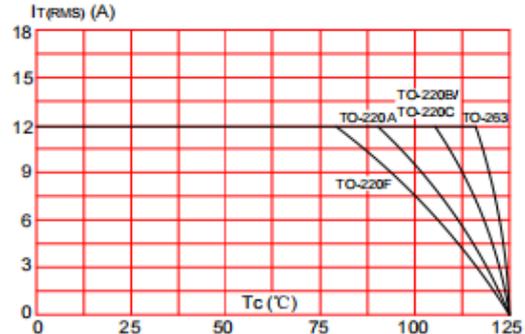


FIG.3: Surge peak on-state current versus number of cycles

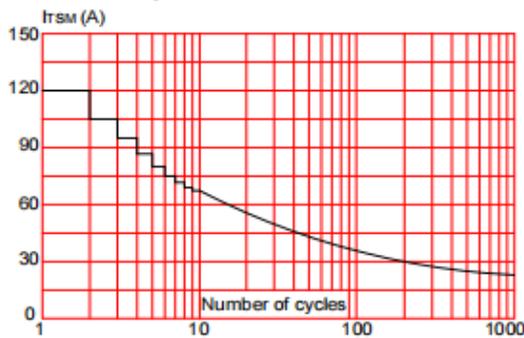


FIG.4: On-state characteristics (maximum values)

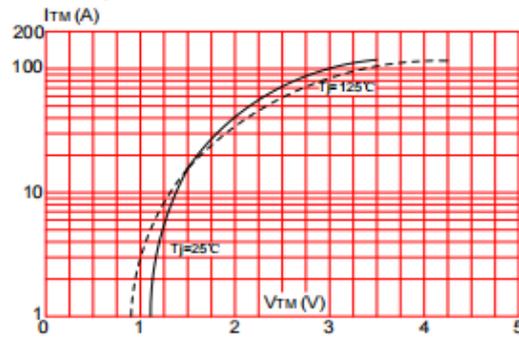


FIG.5: Non-repetitive surge peak on-state current for a sinusoidal pulse with width $t_p < 10\text{ms}$, and corresponding value of $I^2 t$ ($dI/dt < 50\text{A}/\mu\text{s}$)

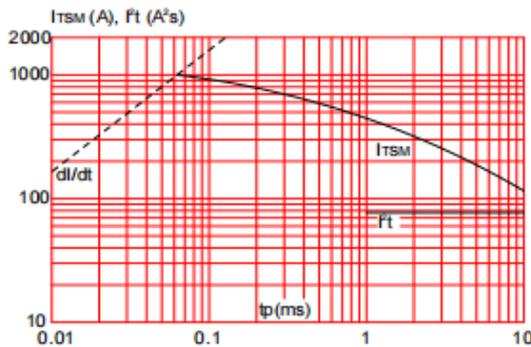
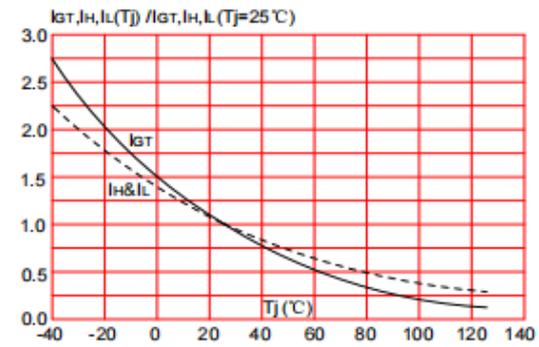


FIG.6: Relative variations of gate trigger current, holding current and latching current versus junction temperature





● TO-220 Dimensional drawing:

Unit: mm (± 0.1)

